

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/532,082	OCHI ET AL.	
Examiner		Art Unit		Page 1 of 1
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2001/0053646	12-2001	Tanaka et al.	442/181
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2004256983 A	09-2004	Japan	SHIMOYAMA et al.	
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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